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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
09/423,948	04/14/2000	LEONID BERESNEV	2345/103	7349		
26646 7	590 03/21/2006		EXAM	EXAMINER		
KENYON & KENYON LLP			NGUYEN, HOAN C			
ONE BROADWAY NEW YORK, NY 10004			ART UNIT	PAPER NUMBER		
NEW TOICE,	111 10004		2871			
			DATE MAILED: 03/21/2006			

Please find below and/or attached an Office communication concerning this application or proceeding.



Office Action Summary		Applica	Application No. Applicant(s)					
		09/423,	948	BERESNEV ET	BERESNEV ET AL.			
		Examin	er	Art Unit				
		HOAN C	C. NGUYEN	2871				
Period fo	The MAILING DATE of this communic or Reply	cation appears on t	he cover sheet v	with the correspondence a	ddress			
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).								
Status								
1) 又	Responsive to communication(s) filed	d on <i>06 January 20</i>)06.		,			
2a)□		b)⊠ This action is						
3)	, 							
٠,۵	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims	•		,				
·		nlication						
•	Claim(s) 6-16 is/are pending in the application.							
	4a) Of the above claim(s) is/are withdrawn from consideration.							
· ·	5) Claim(s) is/are allowed.							
	i) Claim(s) <u>6-16</u> is/are rejected. ') Claim(s) is/are objected to.							
·	•	ion and/or alastian	requirement					
8) Claim(s) are subject to restriction and/or election requirement.								
Application Papers								
9) The specification is objected to by the Examiner.								
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.								
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).								
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.								
Priority under 35 U.S.C. § 119								
12)	Acknowledgment is made of a claim for	or foreian priority u	nder 35 U.S.C.	§ 119(a)-(d) or (f).				
	☐ All b)☐ Some * c)☐ None of:			3 () () () () ()	•			
/-	_	locuments have be	en received					
	 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 							
	3. Copies of the certified copies of the priority documents have been received in this National Stage							
* <	application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received.							
* See the attached detailed Office action for a list of the certified copies not received.								
Attachmen			🗖 .					
1) Undice of References Cited (PTO-892) 4) Interview Summary (PTO-413) Paper No(s)/Mail Date								
	mation Disclosure Statement(s) (PTO-1449 or P			Informal Patent Application (PT	O-152)			
	r No(s)/Mail Date	·	6) 🔲 Other:					
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DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 01/06/2006 has been entered.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 1. Claims 6-8, 10-14 and 16 are rejected under 35 U.S.C. 102(b) as being anticipated by De Lang (US3635552) provided in IDS.

In regard to claims 6 and 12, De Lang teaches a tunable interferometer for measuring an optical surface comprising:

- at least one light source 1;
- a reference surface 5, light from the at least one light source impinging the
 reference surface, the reference surface reflecting a first interference beams

wherein the reference surface is stationary when at least one light source impinges the reference surface 5;

- a test object 12, light from the at least one light source impinging the test object,
 the test object reflecting a second interference beam;
- at least one beam splitter 3, the first interference beam and the second interference beam striking the at least one beam splitter; and
- a polarizer 6 & 7 polarizing the first interference beam and the second interference beam so that the first interference beam and the second interference beam each have a different polarization state relative to one another; and
- an analyzer 10 positioned at an output of the interferometer, the analyzer having a variable polarization state, the analyzer tuning the interferometer as a function of the polarized first interference beam and the second interference beam, wherein depending on the polarization state of the analyzer, an additional phase is introduced into at least one of the first and second interference beams of different polarizations so that an interference fringe pattern is displaced by a distance.

wherein

Claims 7 and 13:

the interferometer is a two-beam interferometer, wherein the light is a linearly polarized light and wherein the polarizer includes a first λ/4 retardation plate 7 allocated to the reference surface, and a second λ/4 retardation plate 6 positioned before the analyzer.

Application/Control Number: 09/423,948 Page 4

Art Unit: 2871

Claims 8 and 14:

• the analyzer includes a rotatable linear analyzer (abstract and col. 3 lines 28-29).

<u>Claims 10 and 16</u>:

• the analyzer is arranged physically separate from the interferometer.

Claim 11:

 the test object 12 is stationary when the at least one light source impinges the test object.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

2. Claims 9 and 15 are rejected under 35 U.S.C. 103(a) as being unpatentable over De Lang (US3635552) as applied to claims 6-8, 10-14 and 16, and in further view of Sharp et al. (US5627666).

De Lang fails to disclose the interferometer having the analyzer including an electrically tunable liquid-crystal element with a linear polarizer.

Sharp et al. teach (Fig. 3) the interferometer (col. 2 lines 20-21) having the analyzer including an electrically tunable liquid-crystal element 10/20 with a linear polarizer 40.

Art Unit: 2871

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to further modify a tunable interferometer as De Lang disclosed with the analyzer including an electrically tunable liquid-crystal element with a linear polarizer for increasing tuning range (col. 2 lines 35-46).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to HOAN C. NGÜYEN whose telephone number is (571) 272-2296. The examiner can normally be reached on MONDAY-THURSDAY:8:00AM-4:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kim H. Robert can be reached on (571) 272-2293. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

HOAN C. NGUYEN Examiner Art Unit 2871

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Page 5